

Complete Spatial Characterisation of EUV Wavefronts

David Lloyd, Kevin O’Keeffe, Simon Hooker



UNIVERSITY OF
OXFORD

Complete Spatial Characterisation of EUV Wavefronts

1. Characterisation

2. Method

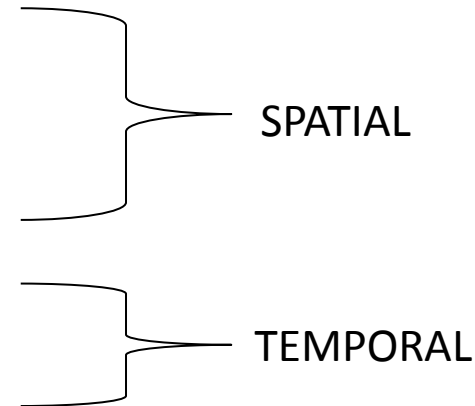
3. Results

4. Outlook

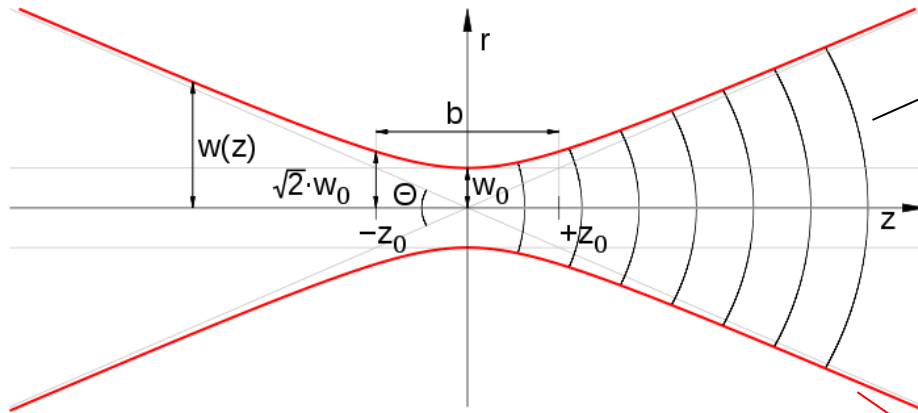
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- Successful design and implementation of (optical) experiments requires knowledge of illuminating radiation.
- Beam characterization concerned with:
 - Transverse intensity profile
 - Transverse phase profile
 - Spatial coherence
 - Temporal pulse shape
 - Temporal coherence

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Spatial Properties



Contour of equal phase – a diverging wave has a curved wavefront with a positive radius of curvature.

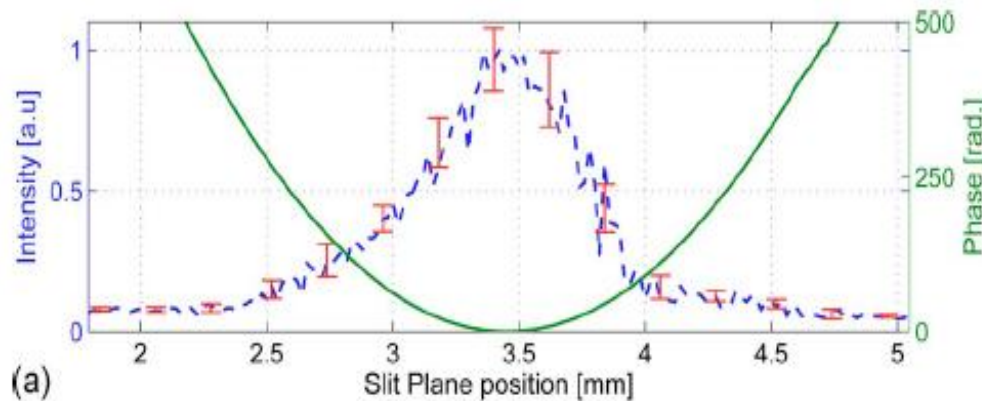
Diagram of a focussed gaussian beam.

Intensity profile widens with increasing distance

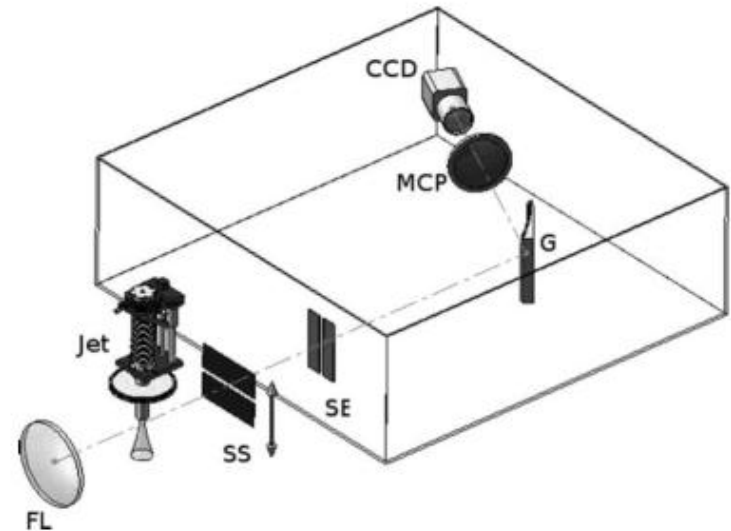
Space-time coupling may be present and is potentially detrimental to experiments.

SWORD

Spectral Wavefront Optical Reconstruction by Diffraction



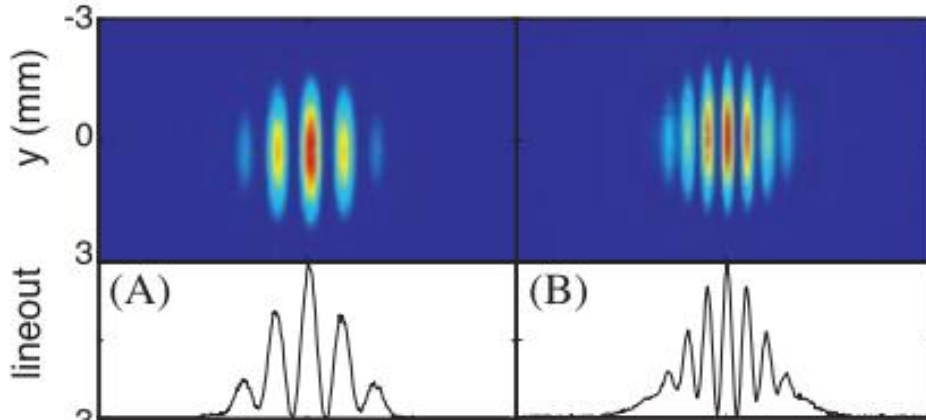
Images taken from [1]



- Scan thin slit transverse to propagation direction.
- Retrieve phase profile from centroid position.
- Retrieve intensity profile from transmitted flux.

[1] E. Frumker et al. Optics Letters, 34:19, 3026-3028 (2009)

Spatial Coherence



Interference fringes from fully coherent phase-matched high harmonic source.
Figure taken from [2]

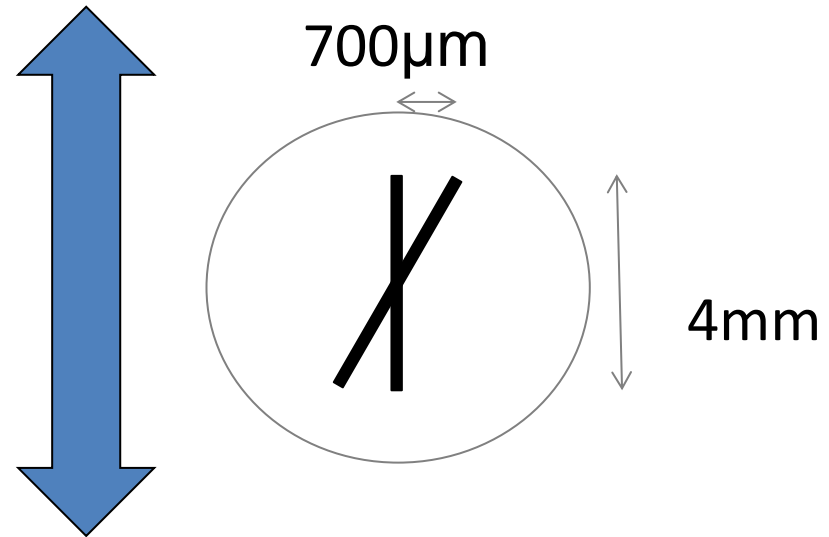
- Coherence defined by correlation by E-field at two separate locations $\langle E_1 E_2^* \rangle$
- Normalised correlation strength is called Complex Degree of Coherence (γ) and is related to fringe visibility (v) through:

$$V = \frac{2\sqrt{I_1}\sqrt{I_2}}{I_1 + I_2} |\gamma|$$

Our technique measures the wavefront and coherence simultaneously.

[2] R Bartels, et al. Science. 297(5580):376 (2002)

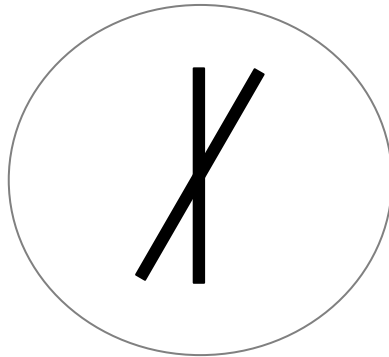
*SCanning
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Measurement
for
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of
Radiation [4]*



- Scan slit in vertical position – continuous change in pinhole separation.
- Incident beam intensity, phase and spatial coherence are retrieved from interference patterns.

[4] Lloyd et. al. *Optics Letters*, 38(7), 1173. (2013)

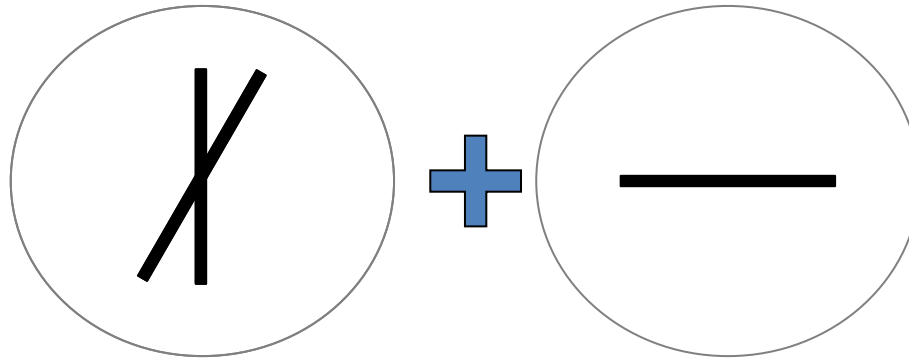
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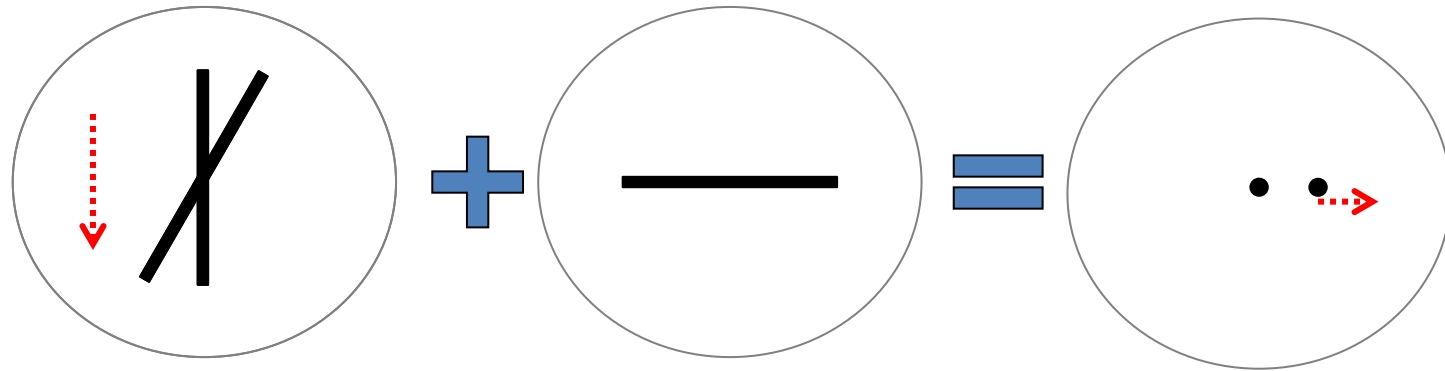
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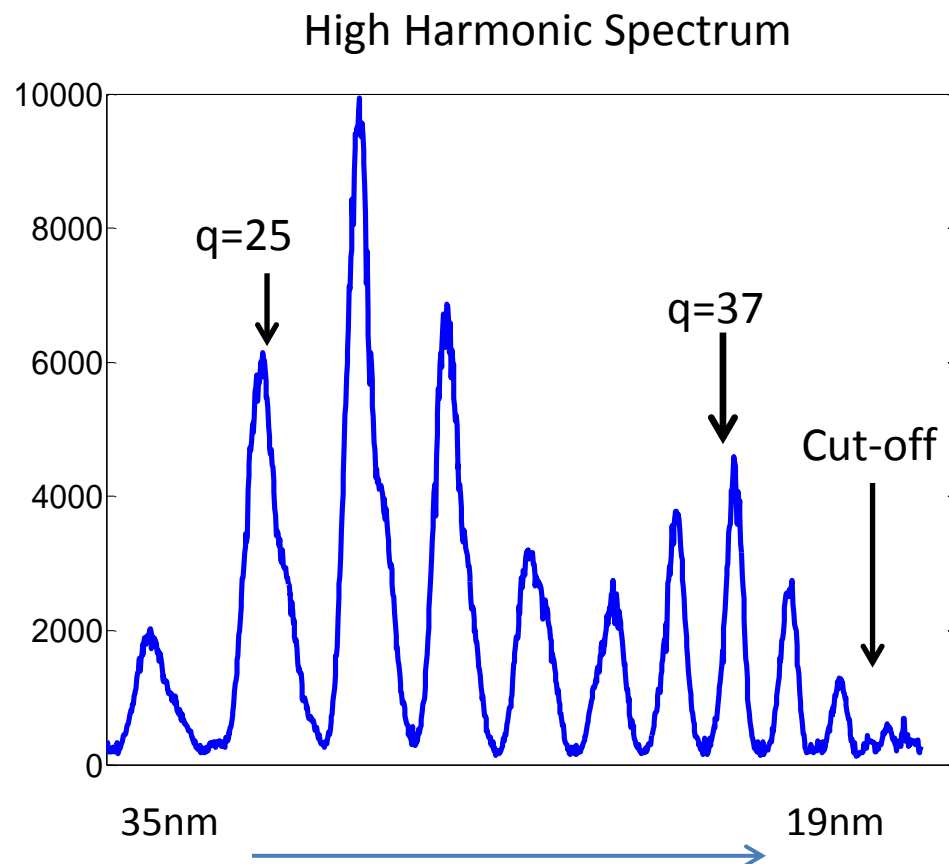
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- Table-top source of EUV/soft x-ray radiation.
- Intense pulses from a (commercial) Ti-Sapphire laser are focused into a noble gas.
- Non-linear interaction produces a frequency comb extending to an abrupt cut-off.
- Odd multiples of laser frequency (harmonic order labelled by q).

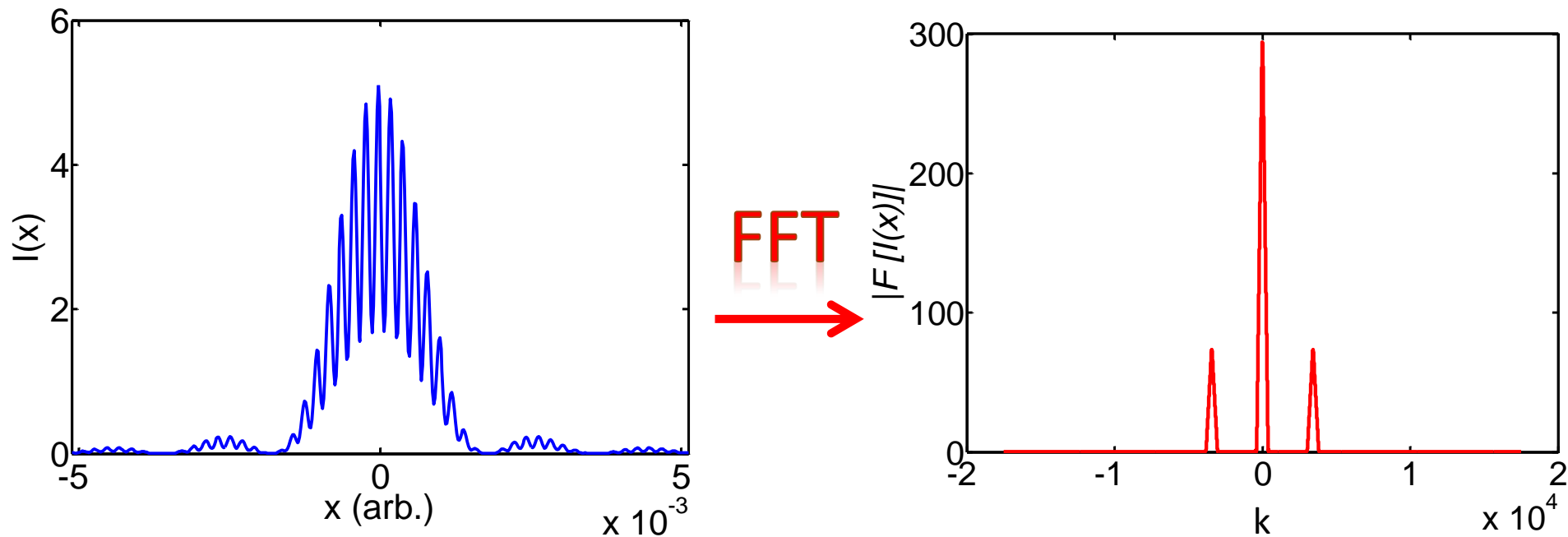


Interference Analysis

Interference pattern from pinholes has the form:

$$I(x) = \varepsilon(x)[1 + V \cos(k_0 x + \varphi)]$$

$$\varepsilon(x) \propto (I_1 + I_2)$$



[5] Takeda et. al. JOSA, Vol. 72, Issue 1, pp. 156-160 (1982)

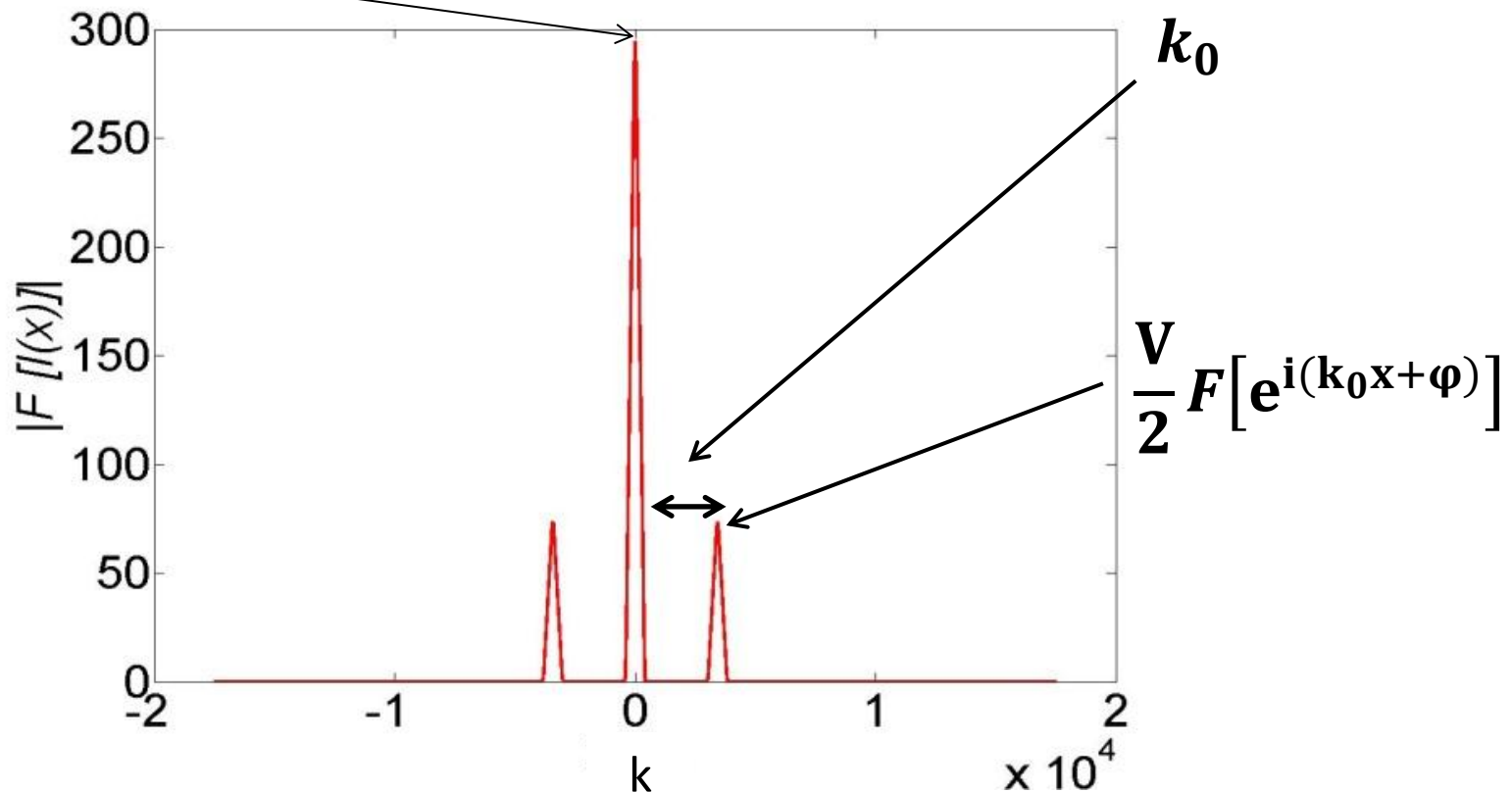
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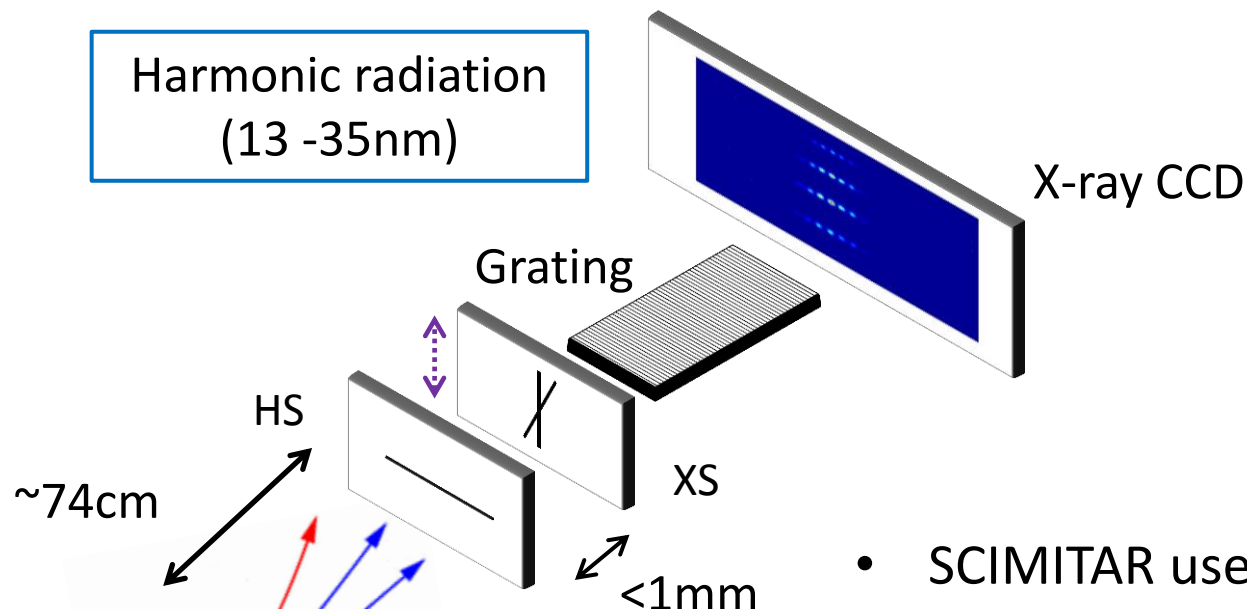
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$F[\varepsilon(x)]$



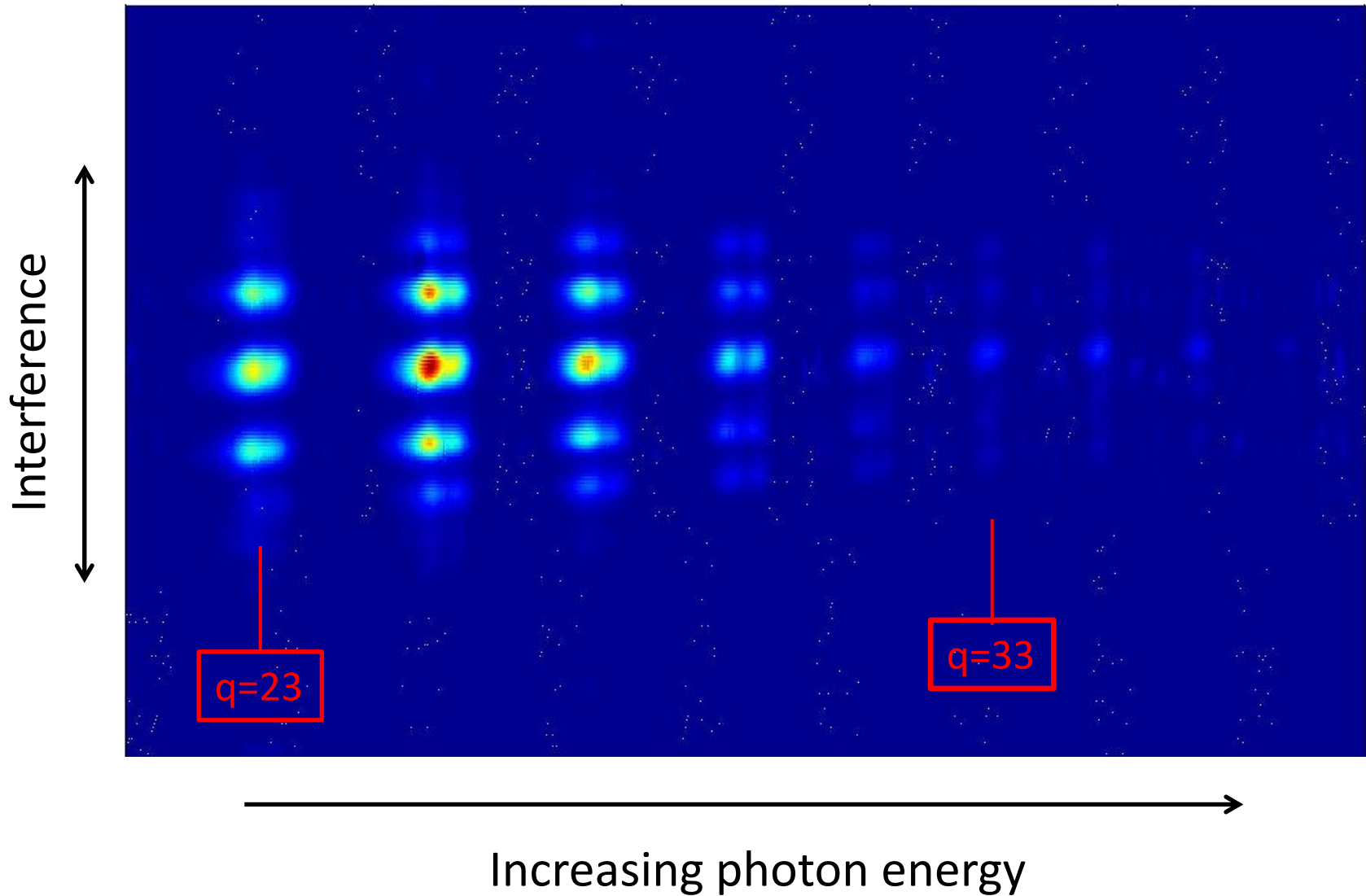
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Experimental Demonstration

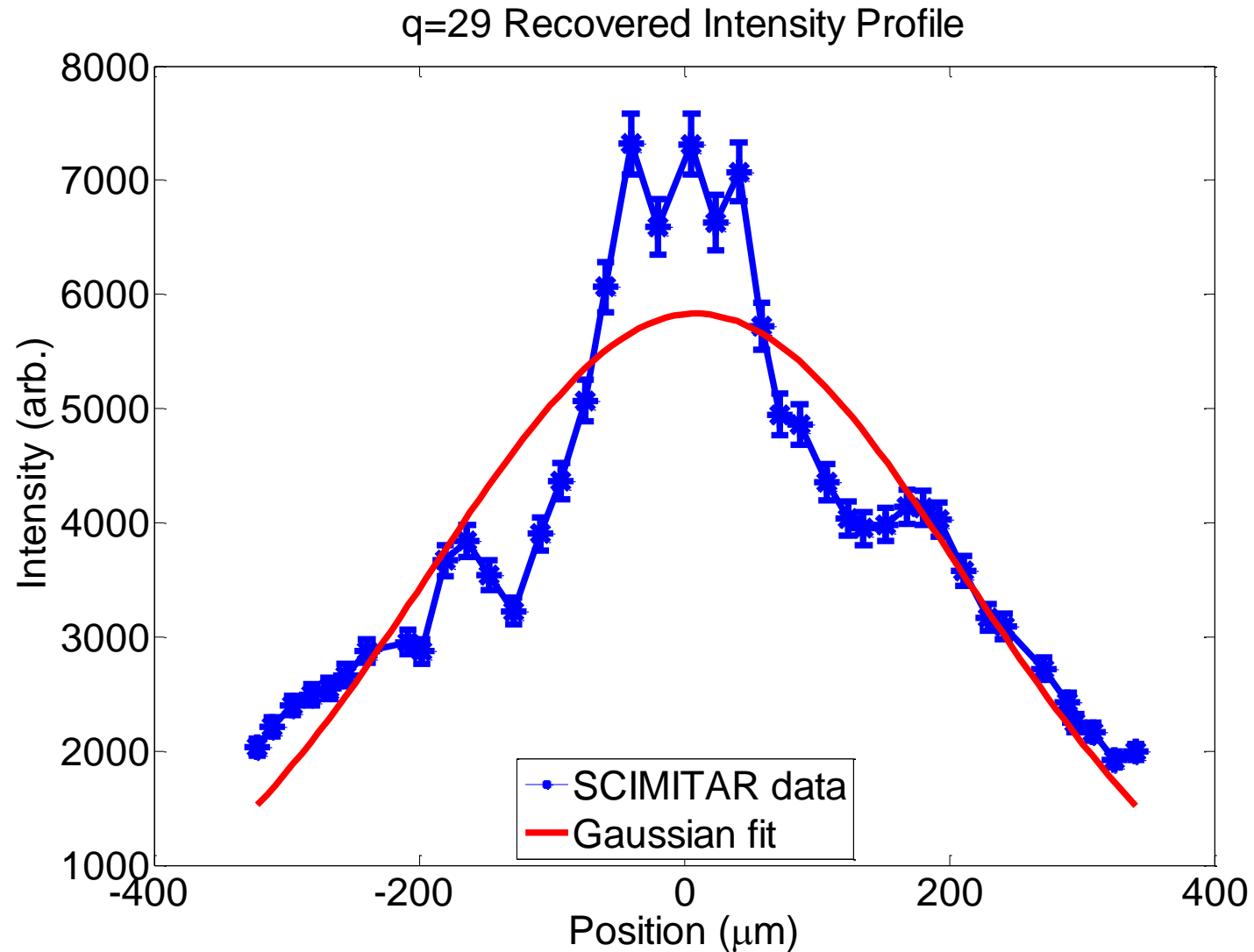


- SCIMITAR used to characterize HHG from a gas cell.
- Driving laser pulse duration tuneable from 12-50 fs.
- Grating allows spectrally resolved characterization.
- Here we show results for 22fs pulses and harmonic orders up to $q=33$.

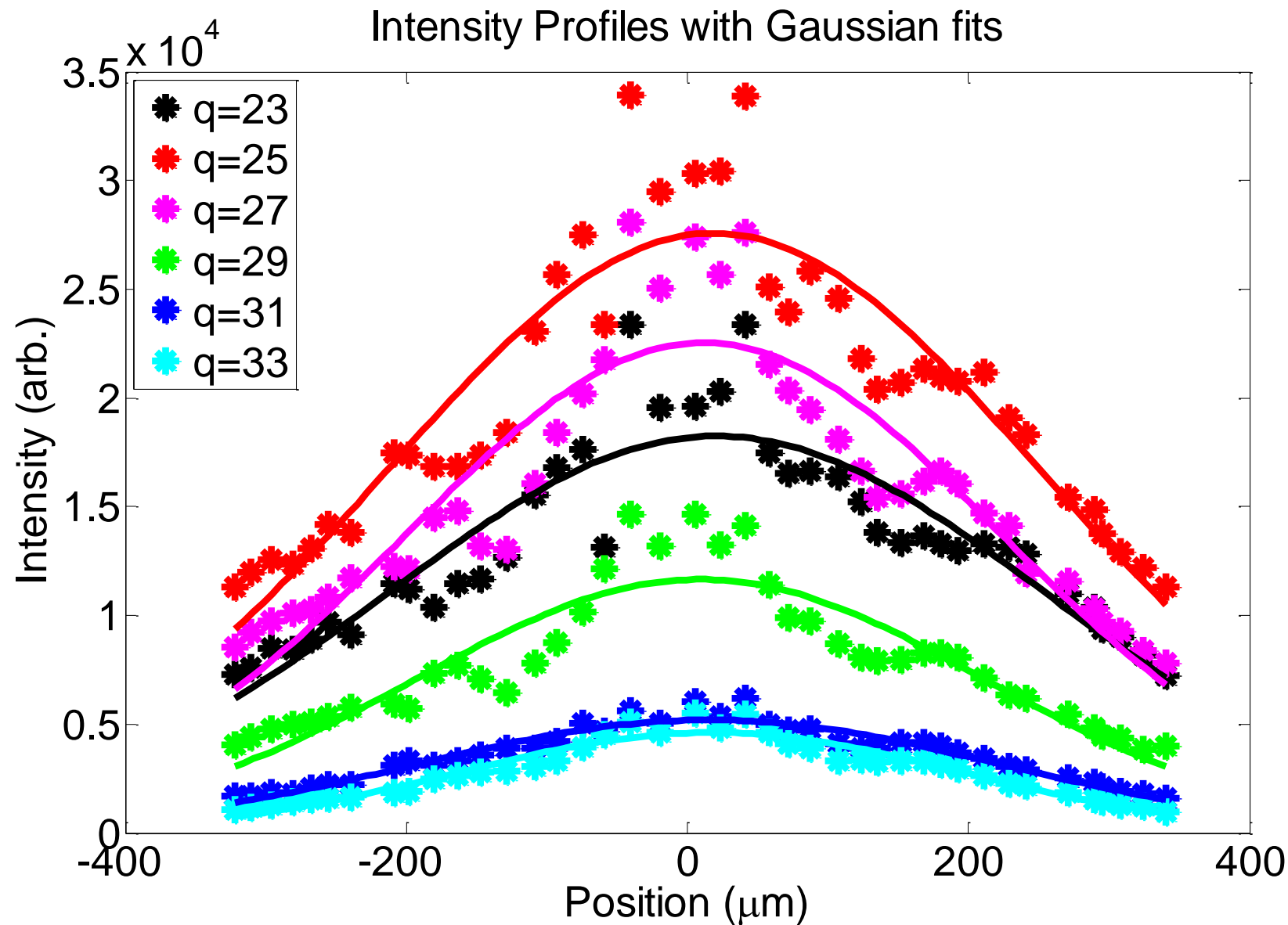
Example Acquisition



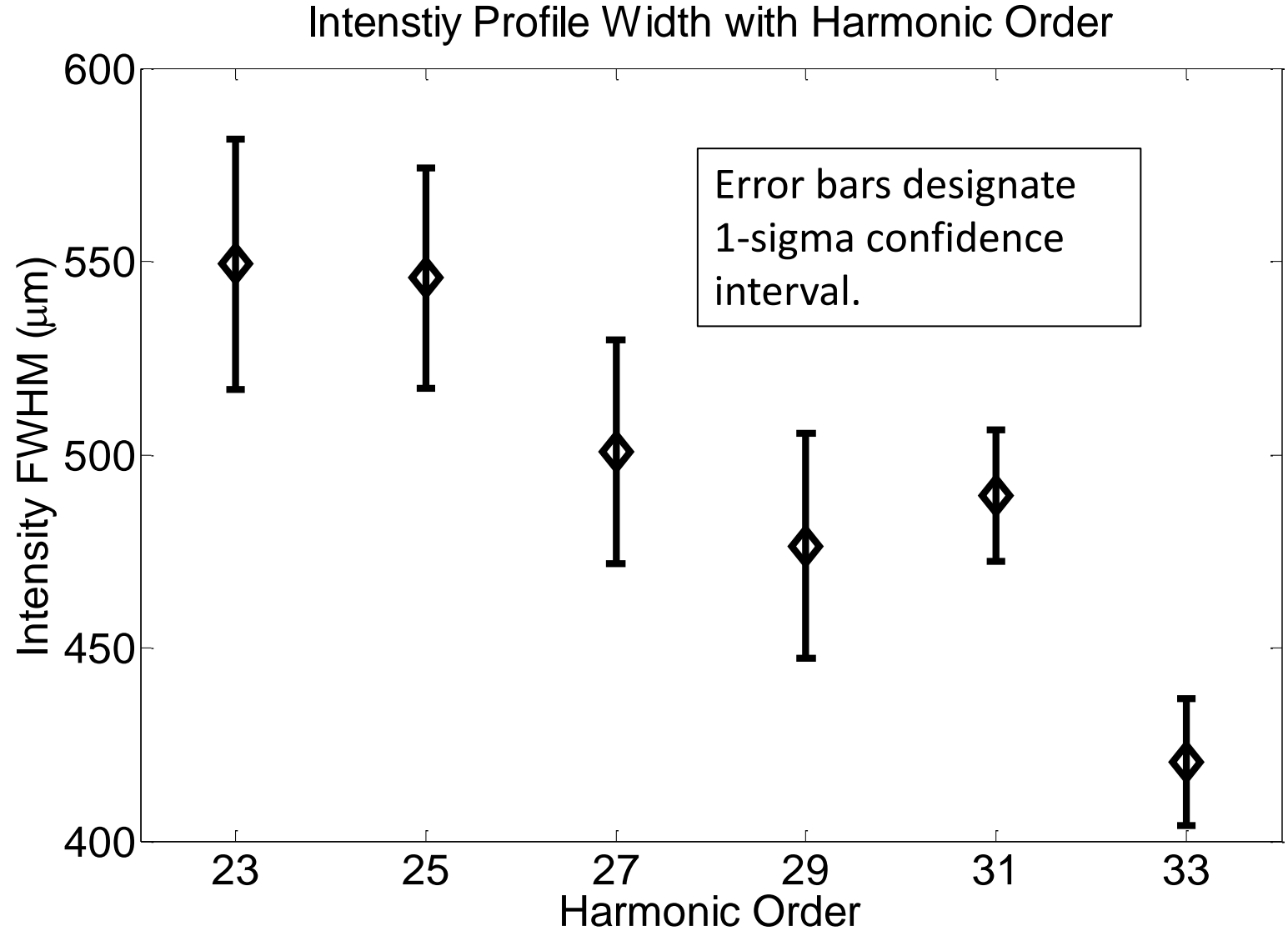
SCIMITAR - Intensity



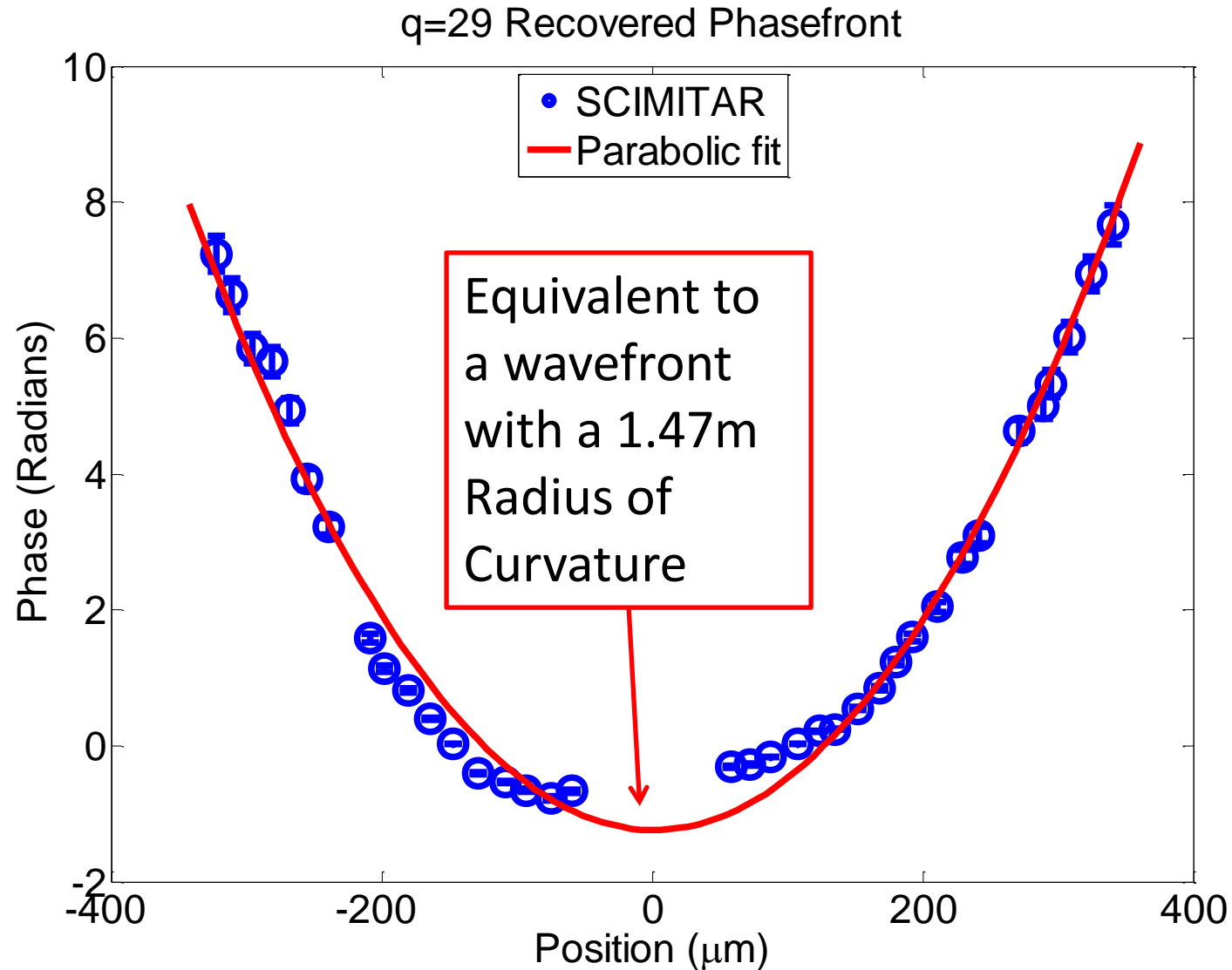
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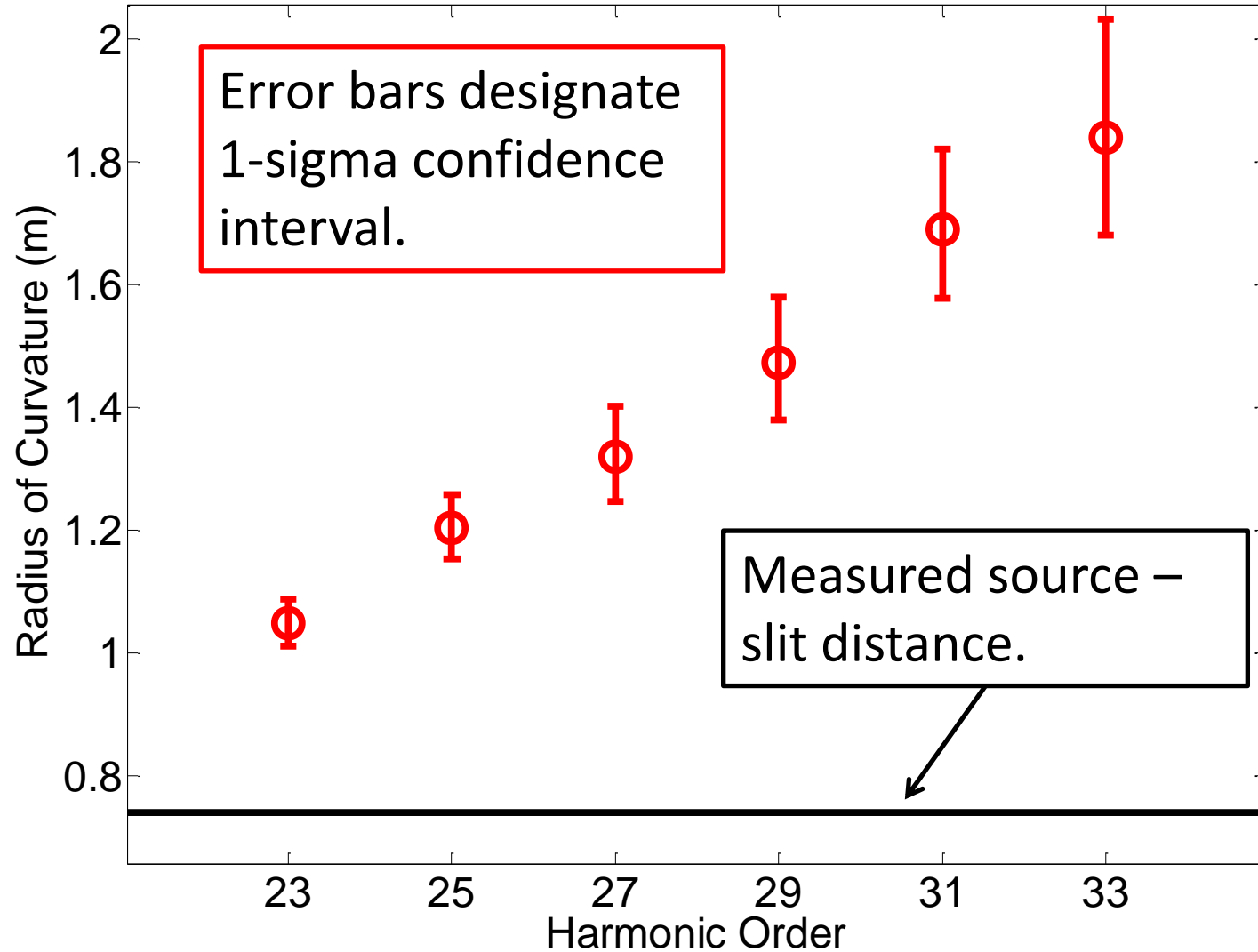


SCIMITAR - Phase

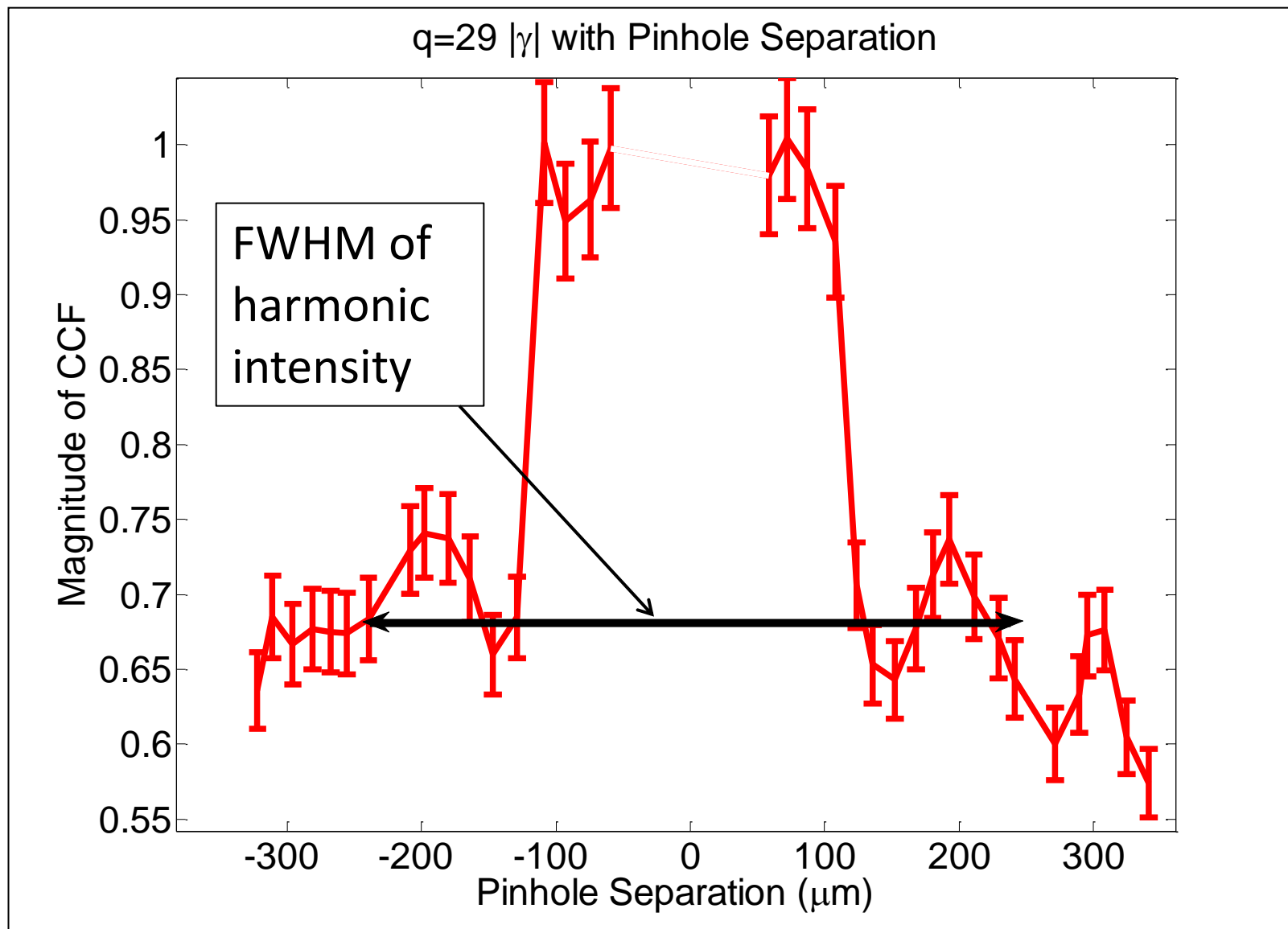


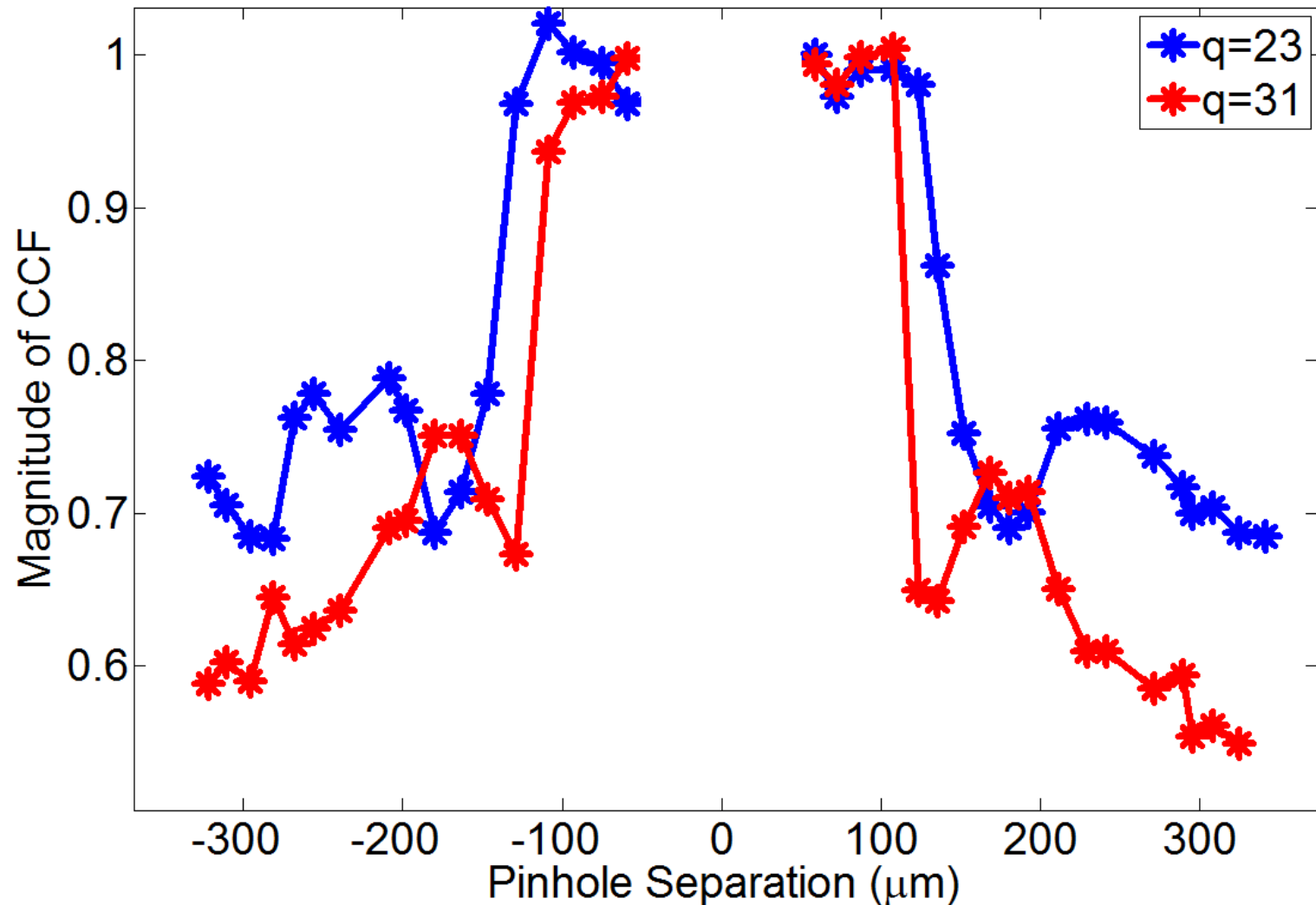
SCIMITAR - Phase

Wavefront Curvature with Harmonic Order

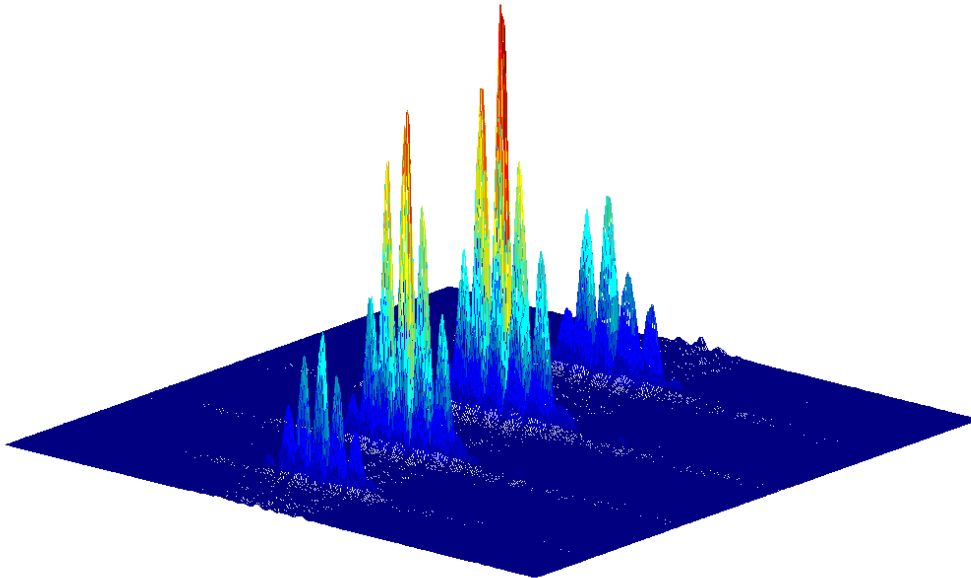


SCIMITAR – Spatial Coherence





- SCIMITAR simultaneously retrieves:
 - Transverse intensity profile
 - Spatial phasefront
 - Spatial Coherence left-right of beam centre
- SCIMITAR is applicable to a wide range of light sources.
- We have demonstrated the technique by characterizing HHG.



Future Work

- Relate results to full theory of partially coherent diffraction (c.f Gaussian – Schell model).

Thank you

EPSRC Engineering and Physical Sciences
Research Council

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Two pinhole “interference” from an incoherent wavefront:

$$I(X) = I_1 \text{Sinc}\left(\frac{kXa}{2z} + \frac{a}{2} \frac{d\varphi}{dX} \Big|_0\right)^2 + I_2 \text{Sinc}\left(\frac{kXa}{2z} + \frac{a}{2} \frac{d\varphi}{dX} \Big|_s\right)^2$$

- Gradient in phase extracted from patterns (similar to SWORD).
- Integrate across transverse direction to retrieve phasefront.
- In this scenario, there is no benefit of using SCIMITAR over SWORD.